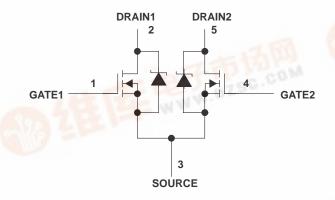
SLIS017 - SEPTEMBER 1992

- Two 7.5-A Independent Output Channels, Continuous Current Per Channel
- Low r<sub>DS(on)</sub> . . . 0.09 Ω Typical
- Output Voltage . . . 60 V
- Pulsed Current . . . 15 A Per Channel
- Avalanche Energy . . . 120 mJ

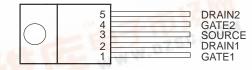
## description

The TPIC2202 is a monolithic power DMOS array that consists of two independent N-channel enhancement-mode DMOS transistors connected in a common-source configuration with open drains.

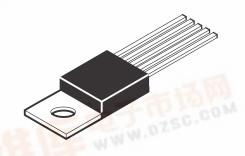
## schematic



# KC PACKAGE (TOP VIEW)



The tab is electrically connected to SOURCE.



## absolute maximum ratings over operating case temperature range (unless otherwise noted)

Drain-source voltage, V <sub>DS</sub>	V
Gate-source voltage, V <sub>GS</sub> ±20 V	
Continuous source-drain diode current	A
Pulsed drain current, each output, all outputs on, ID (see Note 1)	A
Continuous drain current, each output, all outputs on	A
Single-pulse avalanche energy, E <sub>AS</sub> (see Figure 4)	J
Continuous power dissipation at (or below) T <sub>A</sub> = 25°C (see Note 2)	٧
Continuous power dissipation at (or below) T <sub>C</sub> = 75°C, all outputs on (see Note 2)	٧
Operating virtual junction temperature range, T <sub>J</sub>	$\mathcal{C}$
Operating case temperature range, T <sub>C</sub> —40°C to 125°C	$\mathcal{C}$
Storage temperature range, T <sub>stg</sub> –40°C to 125°C	2
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	0

NOTES: 1. Pulse duration = 10 ms, duty cycle = 6%

2. For operation above 25°C free-air temperature, derate linearly at the rate of 16 mW/°C. For operation above 75°C case temperature, and with all outputs conducting, derate linearly at the rate of 0.42 W/°C. To avoid exceeding the design maximum virtual junction temperature, these ratings should not be exceeded.



## **TPIC2202**

## 2-CHANNEL COMMON-SOURCE POWER DMOS ARRAY

SLIS017 - SEPTEMBER 1992

## electrical characteristics, $T_C = 25^{\circ}C$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS					TYP	MAX	UNIT
V <sub>(BR)DS</sub>	Drain-source breakdown voltage	$I_D = 1 \mu A$ ,	V <sub>GS</sub> = 0			60			V
VTGS	Gate-source threshold voltage	$I_D = 1 \text{ mA},$	$V_{DS} = V_{GS}$			1.2	1.75	2.4	V
V <sub>DS(on)</sub>	Drain-source on-state voltage	$I_D = 7.5 A,$	V <sub>GS</sub> = 15 V,	See Note	s 3 and 4		0.68	0.94	V
Inno	Zero-gate-voltage drain current	V <sub>DS</sub> = 48 V,	$V \cap C = \{1\}$		T <sub>C</sub> = 25°C		0.07	1	μА
IDSS	Zero-gate-voltage drain current	VDS = 46 V,			T <sub>C</sub> = 125°C		1.3	10	μΑ
IGSSF	Forward gate current, drain short circuited to source	V <sub>GS</sub> = 20 V,	$V_{DS} = 0$				10	100	nA
IGSSR	Reverse gate current, drain short circuited to source	$V_{GS} = -20 \text{ V},$	V <sub>DS</sub> = 0			10	100	nA	
	Static drain-source on-state	V <sub>GS</sub> = 15 V,	I <sub>D</sub> = 7.5 A,		T <sub>C</sub> = 25°C		0.09	0.125	Ω
rDS(on)	resistance	See Notes 3 an	d 4 and Figures	s 5 and 6	T <sub>C</sub> = 125°C		0.15	0.21	52
9fs	Forward transconductance	$V_{DS} = 15 V$ ,	I <sub>D</sub> = 5 A,	See Note	s 3 and 4	2.5	4.7		S
C <sub>iss</sub>	Short-circuit input capacitance, common source						490		
C <sub>oss</sub>	Short-circuit output capacitance, common source	V <sub>DS</sub> = 25 V,	$V_{GS} = 0$ , $f = 300 \text{ kHz}$			285		pF	
C <sub>rss</sub>	Short-circuit reverse transfer capacitance, common source						90		

NOTES: 3. Technique should limit  $T_J - T_C$  to 10°C maximum.

## source-drain diode characteristics, $T_{\mbox{\scriptsize C}}$ = 25 $^{\circ}\mbox{\scriptsize C}$

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
V <sub>SD</sub>	Forward on voltage	. 754		1'/-lu 400 A/ -		0.8	1.3	V
t <sub>rr</sub>	Reverse recovery time	Is = 7.5 A, Vps = 48 V,	V <sub>GS</sub> = 0, See Figure 1	$di/dt = 100 A/\mu s$ ,		200		ns
Q <sub>RR</sub>	Total source-drain diode charge	100 10 1,				1.5		μС

## resistive-load switching characteristics, $T_{\mbox{\scriptsize C}}$ = 25 $^{\circ}\mbox{\scriptsize C}$

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT
td(on)	Turn-on delay time					12		
td(off)	Turn-off delay time	VDD = 25 V, RE = 0.7 S2, ten = 10 113,	$V_{DD} = 25 \text{ V},  R_L = 6.7 \Omega,  t_{en} = 10 \text{ ns},$			100		ns
t <sub>r</sub>	Rise time		43		115			
t <sub>f</sub>	Fall time					5		
Qg	Total gate charge					13.6	18	
Qgs	Gate-source charge	V <sub>DD</sub> = 48 V, See Figure 3	$I_D = 2.5 A,$	$V_{GS} = 10 \text{ V},$		8.3	11	nC
Q <sub>gd</sub>	Gate-drain charge	gara a				5.3	7	
L <sub>D</sub>	Internal drain inductance					7		nH
LS	Internal source inductance					7		1111

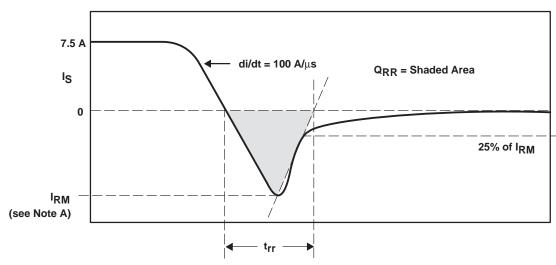
### thermal resistance

PARAMETER		TEST CONDITIONS		TYP	MAX	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	All outputs with equal power			62.5	°C/W
Raic Junction-to-case thermal resistance		All outputs with equal power			2.4	°C/W
R <sub>0</sub> JC	Junction-to-case thermal resistance	One output dissipating power			3.3	°C/W



<sup>4.</sup> These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

### PARAMETER MEASUREMENT INFORMATION



NOTE A: I<sub>RM</sub> = maximum recovery current

Figure 1. Reverse-Recovery-Current Waveforms of Source-Drain Diode

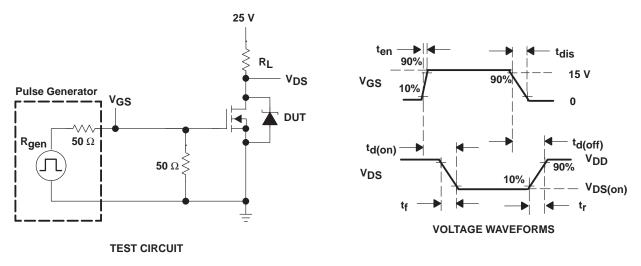


Figure 2. Test Circuit and Voltage Waveforms, Resistive Switching

#### PARAMETER MEASUREMENT INFORMATION

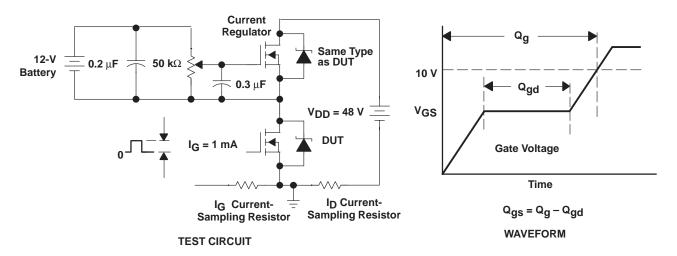
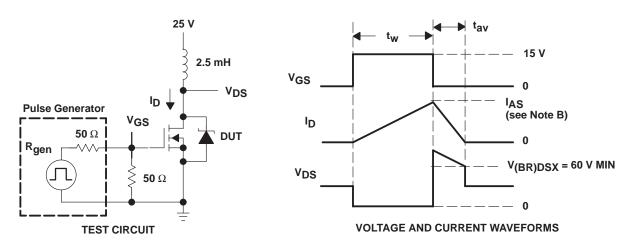


Figure 3. Gate Charge Test Circuit and Waveform



NOTES: A. The pulse generator has the following characteristics:  $t_r \le 10$  ns,  $t_f \le 10$  ns,  $Z_O = 50 \Omega$ .

B. Input pulse duration  $(t_W)$  is increased until peak current  $I_{AS} = 7.5 \text{ A}$ .

Energy test level is defined as 
$$E_{AS} = \frac{I_{AS} \times V_{(BR)DSX} \times t_{av}}{2} = 120 \text{ mJ min.}$$

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms



### **TYPICAL CHARACTERISTICS**

#### STATIC DRAIN-SOURCE ON-STATE RESISTANCE

### **CASE TEMPERATURE** 0.30 $I_D = 7.5 A$ 0.25 <sup>r</sup>DS(on) - Static Drain-Source **VGS = 5 V** On-State Resistance – $\Omega$ 0.20 V<sub>GS</sub> = 10 V 0.15 0.1 \_V<sub>GS</sub> = 15 V V<sub>GS</sub> = 20 V 0.05 0 - 50 - 25 25 50 125 75 100 T<sub>C</sub> - Case Temperature - °C

Figure 5

## 

Figure 7

### STATIC DRAIN-SOURCE ON-STATE RESISTANCE

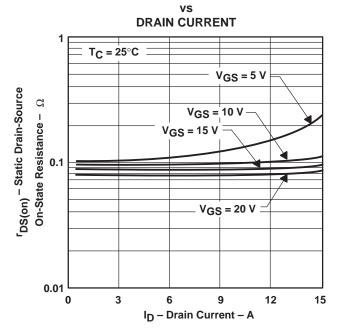


Figure 6

## DRAIN CURRENT

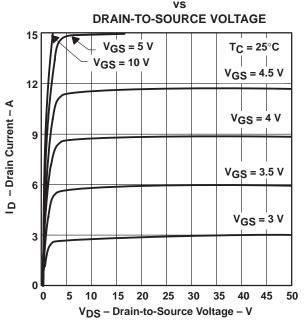


Figure 8

0

- 50

- 25

### **TYPICAL CHARACTERISTICS**

## 

Figure 9

T<sub>C</sub> - Case Temperature - °C

25

50

75

125

100

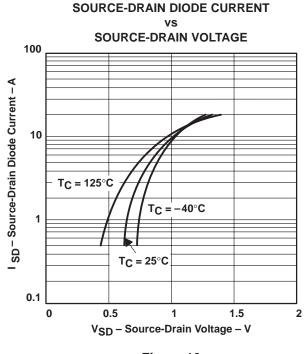


Figure 10

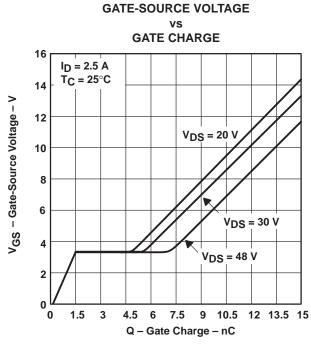


Figure 11

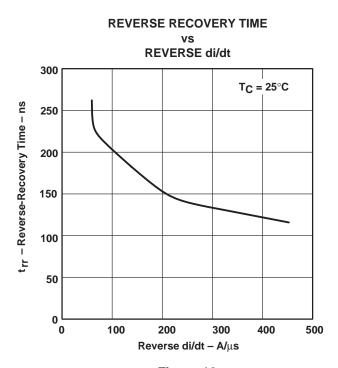


Figure 12



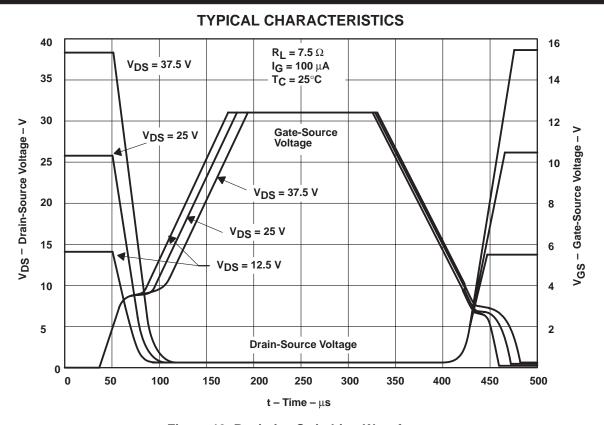


Figure 13. Resistive Switching Waveforms



### THERMAL INFORMATION

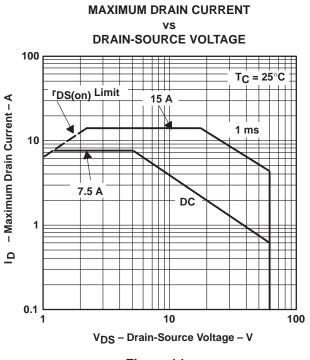
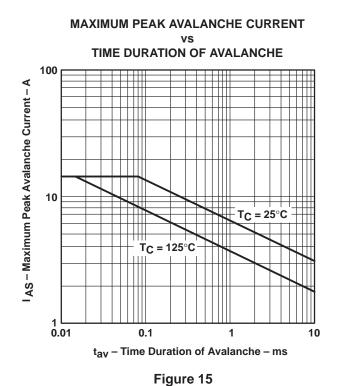


Figure 14

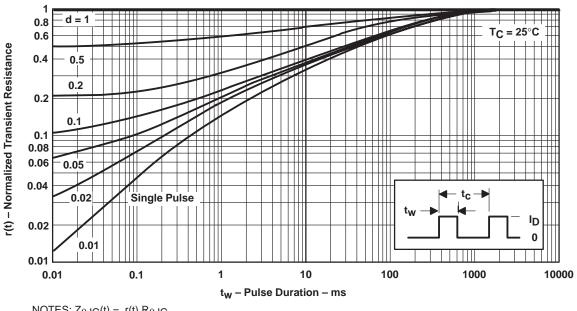


TEXAS

## THERMAL INFORMATION

## NORMALIZED TRANSIENT THERMAL IMPEDANCE

## **SQUARE-WAVE PULSE DURATION**



 $\begin{aligned} \text{NOTES:} \ Z_{\theta JC}(t) &= \ r(t) \ R_{\theta JC} \\ t_W &= \ \text{pulse duration} \\ t_C &= \ \text{period} \\ d &= \ \text{duty cycle} \ = \ t_W/t_C \end{aligned}$ 

Figure 16



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